

# CX-200PLUS

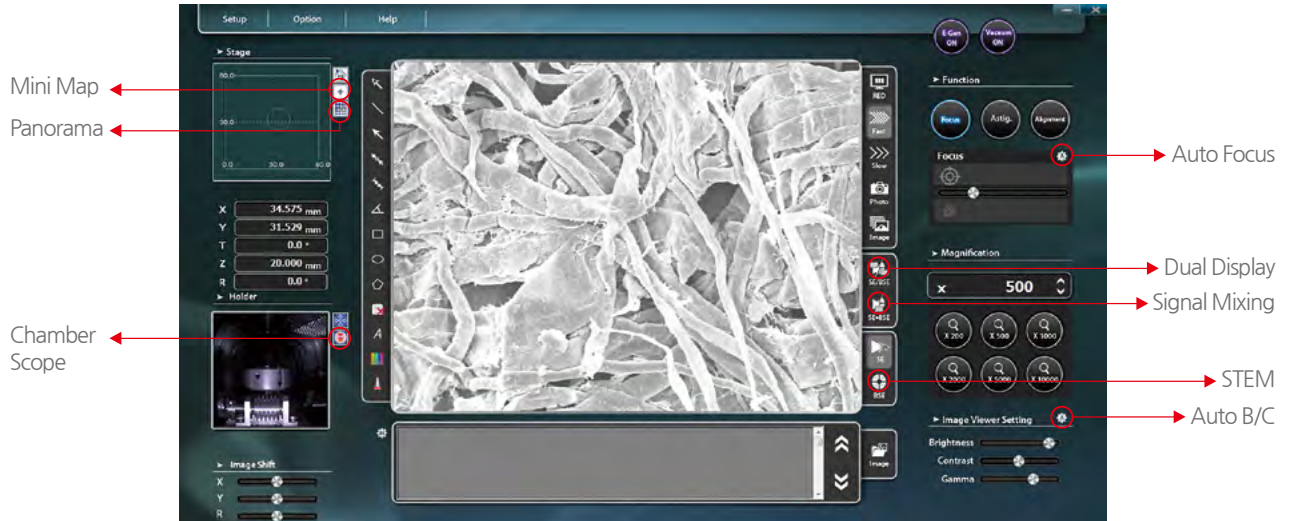
SCANNING  
ELECTRON  
MICROSCOPE



COXEM

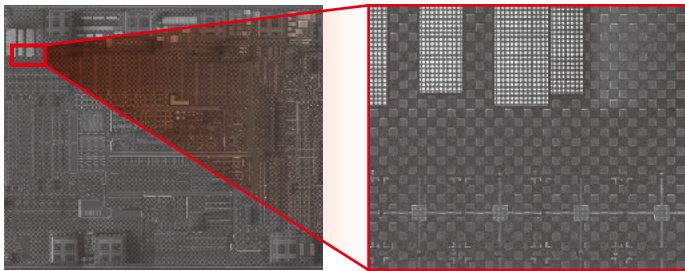
## New NanoStation 4.0™

Experience upgraded functions and new features with the new NanoStation 4.0 GUI such as MiniMap, Panorama Shot, Chamber Scope, Signal Mixing and etc. NanoStation 4.0 provides two different modes for operation: 'EASY' and 'EXPERT'. User can choose their own optimized mode based on experience and proficiency. EASY mode consists of most frequently used functions and upgraded auto functions that allow the entry-level user to operate the SEM in a simplified manner. EXPERT mode includes all functions and allows the advanced user to adjust more parameters in order to obtain the best results.



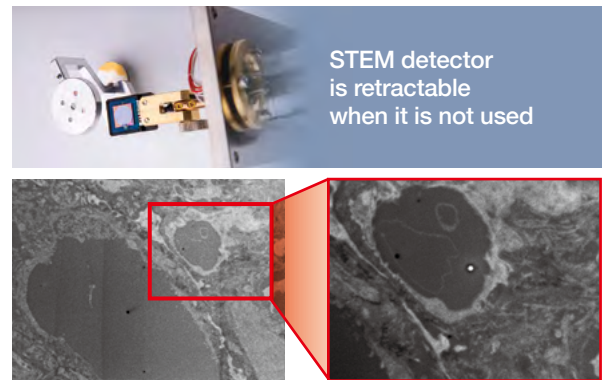
## Panorama

Panorama Shot function in NanoStation 4.0 can combine hundreds or thousands of SEM images side by side into one consolidated image through stitching function. This function enables the user to capture high resolution images of large areas.



## STEM

COXEM offers an annular STEM detector. BF mode and DF mode can be selected. 4 TEM grid specimens can be loaded at once. Precise EDS analysis is possible at the same time without further adjustment.



Large Intestine Cell (Left)x10,000, (Right)x25,000 (DF mode)

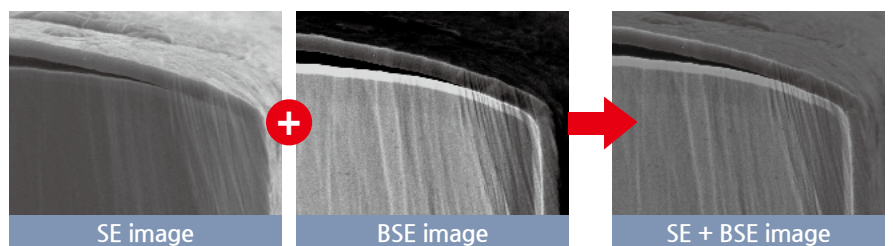
## Dual Display / Signal Mixing

### Dual Display Mode

SE and BSE images can be observed in dual display at the same time.

### Signal Mixing Mode

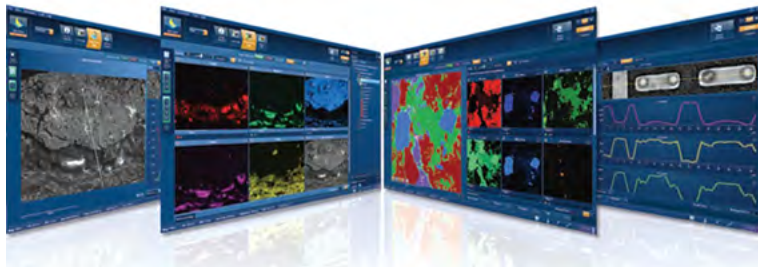
By merging SE and BSE images, the advantages of both images can be observed simultaneously in a composite image.





## EDS

Aztec EDS will change the way you view your data, gathering more accurate results, gaining more insights, seeing everything in stunning high resolution, and finishing the job faster than ever.



Aztec Energy



20mm<sup>2</sup>

50mm<sup>2</sup>

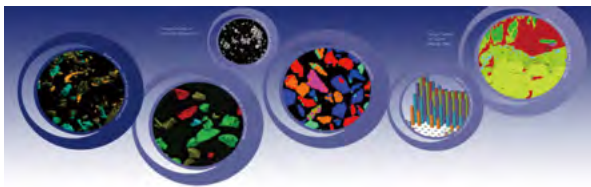
80mm<sup>2</sup>

150mm<sup>2</sup>

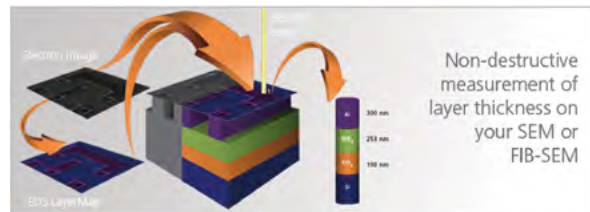
X-Max

## Feature/ GSR / LayerProbe

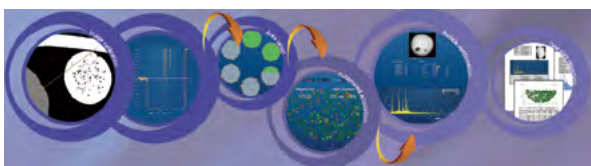
Aztec Feature combines the raw speed and sensitivity of the X-max Silicon Drift Detector with the superior analytical performance and ease of use of the Aztec EDS analysis suite to create the most advanced automated particle analysis platform on the market.



Feature Analysis



Non-destructive measurement of layer thickness on your SEM or FIB-SEM



GSR

LayerProbe is an exciting new software tool for thin film analysis in the SEM. An option for Aztec EDS microanalysis system, LayerProbe is faster, more cost-effective and higher resolution than dedicated thin film measurement tools.

- Thin Film analysis in the SEM
- Characterizes multiple layers beneath surface of the specimen
- Non destructive analysis
- Lateral resolution down to 200nm
- Easy to set-up for routine user, and a cost effective extension of SEM

## EBSD

Symmetry delivers uncompromised class leading performance on all samples, transforming EBSD workflows. Exceptional analysis speeds in excess of 3,000pps on real-world samples are balanced by extreme sensitivity, high pattern resolution and a range of innovative design features.



Symmetry



AZtechKL EBSD

## Specification

Resolution SE	3.0nm at 30kV 8.0nm at 3kV
Resolution BSE	4.0nm at 30kV
Magnification	x15 to x300,000
Digital Zoom	x2, x4
Acceleration Voltages	1 to 30kV
Maximum Specimen Size	160mm in Diameter
Specimen Stage	5-Axis Motorized
X	0~60mm
Y	0~60mm
Z	5~60mm
R	360°
T	-20~90°
Observation Area	70mm in Diameter
Maximum Height	55mm
Stage Control	Eucentric
Electron Gun	Pre-centered Cartridge
Source	Tungsten
Detector	SED BSED
Control	Mouse Keyboard
Auto Image Adjustment	Auto Focus Auto Brightness & Contrast Auto Filament Saturation Auto Start
Special Features	Dual Display Signal Mixing Comp/Topo Navigation Panorama (Large Area) Chamber Scope

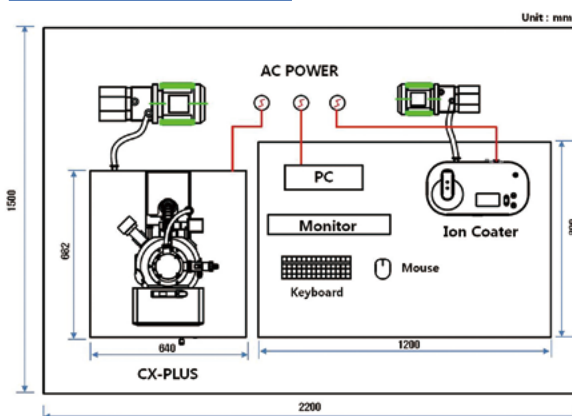
## Optional Products

CL Detector
EDS (Oxford, Bruker)
EBS (Oxford, Bruker)
WDS (Oxford, Bruker)
STEM (BF, DF mode)
Nanomanipulators
Cool Stage (-30°C to 50°C)

## Installation Condition

Power	110V/ 220V, 50/60Hz, Ground 3V, Capacity 1kVA
Vibration	Less than 35dB
Magnetic Field	Less than 0.50mG
Sound Noise	Less than 60dB
Temperature	20°C ±5°C
Humidity	Less than 70%

## Installation Space



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